

<b>Notice of References Cited</b>	Application/Control No. <div style="text-align: center;"><b>09/451,097</b></div>		
	Applicant(s)/Patent Under Reexam <div style="text-align: center;"><b>Watanabe</b></div>		
	Examiner <div style="text-align: center;"><b>Richard Lee</b></div>	Art Unit <div style="text-align: center;"><b>2613</b></div>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	5,978,030	11/1999	Jung et al	375	240.16
B	6,400,890	6/2002	Nagasaka et al	386	69
C	5,805,746	9/1998	Miyatake et al	382	236
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**FOREIGN PATENT DOCUMENTS**

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N						
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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